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Naslov	URL	Autori	Naslov izvornika
Razvoj in situ postava za optičku karakterizaciju implantiranih NV centara boje u dijamantu		Žužić, Livio	
In situ detection of single ions implanted in diamond		Vićentijević, Milan	
Chemical imaging of organic materials with MeV SIMS using a continuous collimated ion beam		Siketić, Zdravko; Bogdanović-Radović, Ivančica; Barac, Marko; Brajković, Marko; Siketic, Zdravko	
Mjerenje zaustavne moći za ione vodika MeV-skih energija u dijamantu		Matijević, Matija	
Low energy MeV SIMS yield measurements of various inorganic samples		Barac, Marko; Siketić, Zdravko; Brajković, Marko; Bogdanović-Radović, Ivančica	
MeV SIMS analysis of irradiation effects on molecular signatures		Barac, Marko; Siketić, Zdravko; Brajković, Marko; Krmpotić, Matea	
MeV TOF SIMS determination of deposition order between optically distinguishable and indistinguishable inks		Barac, Marko; Bogdanović-Radović, Ivančica; Brajković, Marko; Siketić, Zdravko	
Spatially resolved metabolic composition in seeds of common bean: comparison of the low phytic acid mutant and the wild type		Barac, Marko; Siketić, Zdravko; Bogdanović-Radović, Ivančica; Brajković, Marko	
Imaging of Organic Samples with Megaelectron Volt Time-of-Flight Secondary Ion Mass Spectrometry Capillary Microprobe		Brajković, Marko; Bogdanović-Radović, Ivančica; Barac, Marko; Cosic, Domagoj; Siketić, Zdravko	
Development of MeV TOF-SIMS capillary microprobe at the Ruder Boskovic Institute in Zagreb		Brajković, Marko; Barac, Marko; Cosic, Domagoj; Bogdanović-Radović, Ivančica; Siketić, Zdravko	
Dependence of MeV TOF SIMS secondary molecular ion yield from phthalocyanine blue on primary ion stopping power		Brajković, Marko; Siketić, Zdravko; Bogdanović-Radović, Ivančica; Barac, Marko	
Primjena pozicijsko osjetljivih PIN dioda u EBS spekrometriji		Brajković, Marko	

Provjera mjerениh udarnih presjeka za $^{12}\text{C}(\text{p},\text{p})^{12}\text{C}$, $^{16}\text{O}(\text{p},\text{p})^{16}\text{O}$ i $\text{natSi}(\text{p},\text{p})\text{natSi}$ reakcije		Obajdin, Nevena	
Spektroskopija elastično izbijenih iona mjerenjem vremena proleta		Siketić, Zdravko	